Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/014,854	SHIOZAWA ET AL.
Examiner	Art Unit
Jason M. Perilla	2638

	SEAR	CHED	
Class	Subclass	Date	Examiner
375	316	9/2/2005	ĴΡ
710	28	12/22/2005	JP
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH (INCLUDING SEAF)
	DATE	EXMR
East ' USPAT/USPGPUB	9/2/2005	JP
Inventor Name Search EAST/EDAN	12/22/2005	JP